Abraham Arias

List of Publications by Year
in descending order

16 papers	151 citations	1307594 7 h-index	1125743 13 g-index
16 all docs	16 docs citations	16 times ranked	277 citing authors

#	Article	IF	Citations
1	Structural and optical properties of Î²-Ga2O3 thin films grown by plasma-assisted molecular beam epitaxy. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2016, 34, .	1.2	46
2	Synthesis of high purity nickel oxide by a modified sol-gel method. Ceramics International, 2019, 45, 11403-11407.	4.8	27
3	Structural, Optical, and Electrical Characterization of Î²-Ga₂O₃ Thin Films Grown by Plasma-Assisted Molecular Beam Epitaxy Suitable for UV Sensing. Advances in Materials Science and Engineering, 2018, 2018, 1-6.	1.8	18
4	Structural and electrical characterization of multilayer Al2O3/ZnO nanolaminates grown by atomic layer deposition. Materials Science in Semiconductor Processing, 2017, 71, 290-295.	4.0	14
5	Gold, copper and gold/copper bimetallic nanoparticles obtained by focused ion beam sputter deposition and rapid thermal annealing. Vacuum, 2018, 157, 166-172.	3.5	10
6	Application of Metal-Oxide-Semiconductor structures containing silicon nanocrystals in radiation dosimetry. Open Physics, 2015, 13, .	1.7	8
7	Structural, compositional and electrical characterization of Si-rich SiOx layers suitable for application in light sensors. Materials Science in Semiconductor Processing, 2015, 37, 229-234.	4.0	7
8	UV Sensitivity of MOS Structures with Silicon Nanoclusters. Sensors, 2019, 19, 2277.	3.8	7
9	Ultrahigh purity beta gallium oxide microstructures. Ceramics International, 2022, 48, 25322-25325.	4.8	5
10	TEM and Spectroscopic Ellipsometry studies of multilayer gate dielectrics containing crystalline and amorphous Si nanoclusters. Physica E: Low-Dimensional Systems and Nanostructures, 2013, 51, 111-114.	2.7	4
11	UV Dosimeters Based on Metal-Oxide-Semiconductor Structures Containing Si Nanocrystals. Sensor Letters, 2015, 13, 561-564.	0.4	2
12	Visible Light Sensor Based on Metal-Oxide-Semiconductor Structure. Key Engineering Materials, 2014, 605, 384-387.	0.4	1
13	Electrical Characterization of Interface Defects in MOS Structures Containing Silicon Nanoclusters. Advanced Materials Research, 2014, 976, 129-132.	0.3	1
14	MOS Structures Containing Si Nanocrystals for Applications in UV Dosimeters. Key Engineering Materials, 0, 605, 380-383.	0.4	1
15	Electrical Characterization of MOS Structures with Silicon Nanocrystals Suitable for X-Ray Detection. Key Engineering Materials, 0, 543, 150-153.	0.4	0
16	Application of Metal-Oxide-Semiconductor Structures for Visible and Near UV Light Sensing. Sensor Letters, 2015, 13, 556-560.	0.4	0